Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/748,158	MURAYAMA ET AL.
Examiner	Art Unit
Tuan Quach	2826

SEARCHED						
Class	Subclass	Date	Examiner			
257	197, 198, 201, 565	1/29/2005	ΤΩ			
	:					

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
257	197-201	1/31/2005	TQ			
257	565	1/31/2005	TQ			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT; USPGPUB; EPO; JPO; DERWENT; IBMTDB)	1/29/2005	TQ		
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